

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10736698	CHEN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	GERMAN VIANA DI PRISCO	2617

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	328	4/3/2008	GV

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	4/3/2008	GV
Inventor name and Assignee search in PALM ExPO and EAST	4/3/2008	GV
EPO Database( <a href="http://ep.espacenet.com">http://ep.espacenet.com</a> )	4/3/2008	GV
Consulted with Rafael Perez-Gutierrez	4/3/2008	GV
Updated search	10/15/2008	GV

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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